

L Number	Hits	Search Text	DB	Time stamp
1	4	"6338001"	USPAT; EPO; JPO; DERWENT; USOCR	2003/08/01 13:28
2	77	"automatic defect classification"	USPAT; EPO; JPO; DERWENT; USOCR	2003/08/01 13:28
3	0	"automatic defect classification" and (voltage adj contrast)	USPAT; EPO; JPO; DERWENT; USOCR	2003/08/01 13:29
4	8	"automatic defect classification" and voltage	USPAT; EPO; JPO; DERWENT; USOCR	2003/08/01 13:33
5	0	"automatic defect classification" and (voltage adj defect)	USPAT; EPO; JPO; DERWENT; USOCR	2003/08/01 13:33
6	31	wafer and (voltage adj defect)	USPAT; EPO; JPO; DERWENT; USOCR	2003/08/01 13:38
7	130	wafer and (voltage adj contrast)	USPAT; EPO; JPO; DERWENT; USOCR	2003/08/01 13:38
8	52	(wafer and (voltage adj contrast)) and inspection	USPAT; EPO; JPO; DERWENT; USOCR	2003/08/01 13:39